DRAM Simulator

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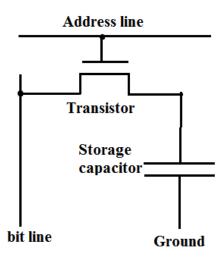
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Outline

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- DRAM controller
- Simplified DRAM Simulator
 - Timing Specification
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Introduction

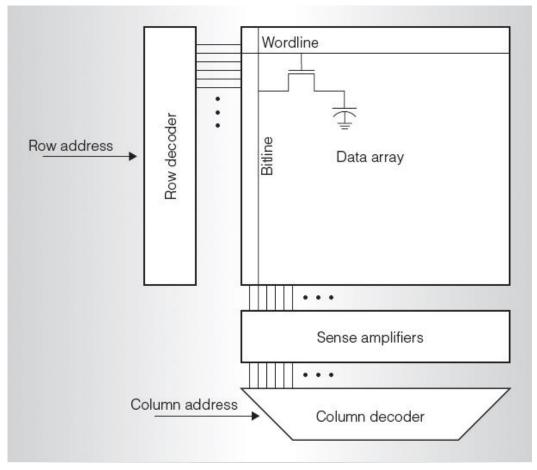
- Dynamic random-access memory (dynamic RAM or DRAM) is a type of random-access semiconductor memory.
- Consisting only a capacitor and a transistor for each bit of data.
- The electric charge on the capacitors slowly leaks off.
 - > refresh!



Introduction

■ Three Basic Operations

- >Row Access
- Column Access
- >Pre-charge

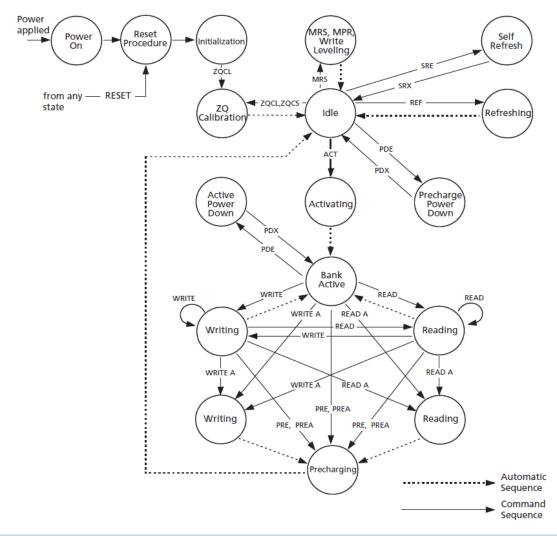


DRAM controller

- Ensure correct operation of DRAM
 - Address Mapping, refresh and timing
- Translate request to DRAM command sequences
- Buffer and schedule requests to improve performance
 - >Reordering, row-buffer, bank, rank, bus management
- Manage power consumption and thermals in DRAM
 - Turn off/on DRAM chips, manage power modes

DRAM controller

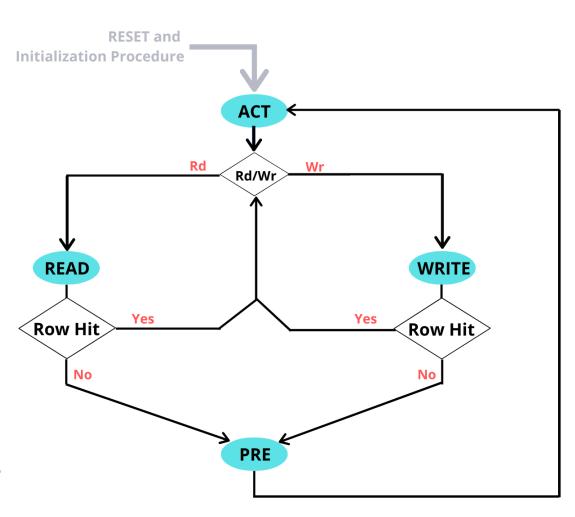
State diagram



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Simplified DRAM Simulator

- Act : Activate row
 - > RASn = low
 - > CASn = high
 - > WEn = 4'hf
- READ: Read operation and access column address
 - > RASn = high
 - > CASn = low
 - > WEn = 4'hf
- WRITE: Write operation and access column address
 - > RASn = high
 - > CASn = low
 - > WEn = 4'h0 (for a word)
- PRE : Pre-charge
 - > RASn = low
 - > CASn = high
 - \rightarrow WEn = 4'h0
 - The address should be the same as the one that activated last time.

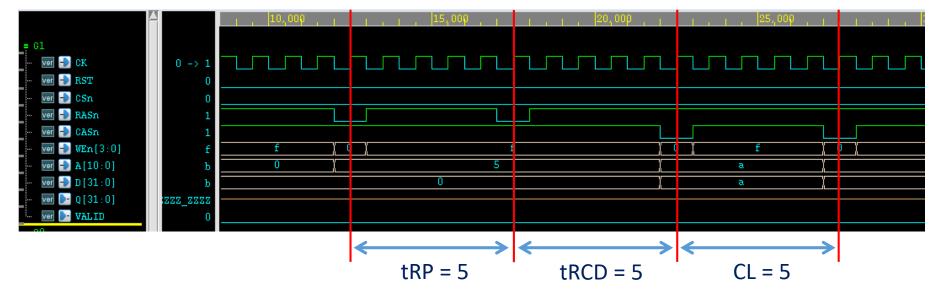


Simplified DRAM Simulator

| | System signals | | | |
|------|----------------|--------|----|----------------------------|
| | CK | input | 1 | System clock |
| DRAM | RST | input | 1 | System reset (active high) |
| | Memory ports | | | |
| | CSn | input | 1 | DRAM Chip Select |
| | | | | (active low) |
| | WEn | input | 4 | DRAM Write Enable |
| | | | | (active low) |
| | RASn | input | 1 | DRAM Row Access Strobe |
| | | | | (active low) |
| | CASn | input | 1 | DRAM Column Access Strobe |
| | | | | (active low) |
| | A | input | 11 | DRAM Address input |
| | D | input | 32 | DRAM data input |
| | Q | output | 32 | DRAM data output |
| | VALID | output | 1 | DRAM data output valid |
| | Memory space | | | |
| | Memory_byte0 | reg | 8 | Size: [0:2097151] |
| | Memory_byte1 | reg | 8 | Size: [0:2097151] |
| | Memory_byte2 | reg | 8 | Size: [0:2097151] |
| | Memory_byte3 | reg | 8 | Size: [0:2097151] |

[★] Row address is 11-bit and column address is 10-bit

Timing Specification

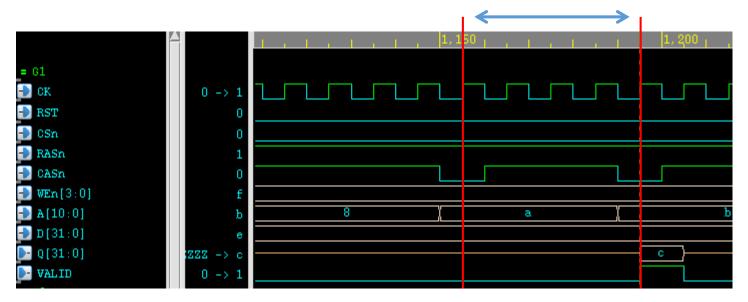


- tRP -Precharge TimeDelay time until the next RAS is asserted
- **tRCD** -Row Address to Column Address Delay Active to Read/Write command time
- CL -CAS Latency
 Delay time between the READ command and the moment data is available

Timing Specification

If the transition violates the timing specification, it will show error or terminates the execution.

4 cycles, but at least 5 cycles.



```
ncsim: *E,ASRTST (./DRAM.sv,149): (time 1195 NS) Assertion test.M1.CL_check has failed

*** CL Violation ! CASn should have more than 5 cycles interval ***
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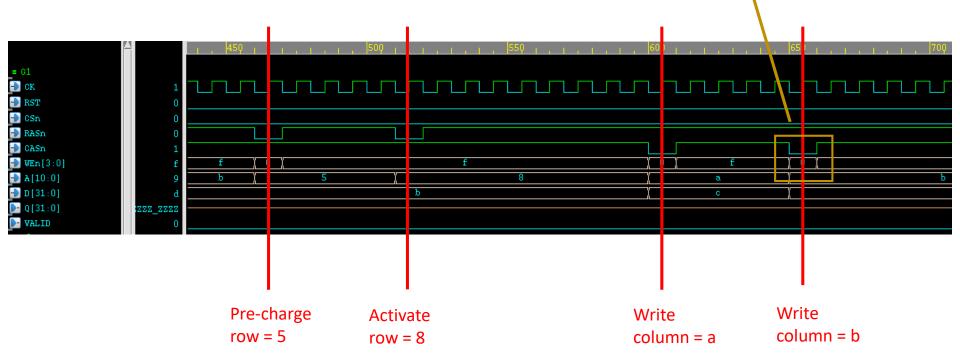
Waveform

- ightharpoonup RAS ightharpoonup Set Row
 - >A should be ready
- CAS → Set Column
 - >READ : A and WEn should be ready
 - WRITE : A, WEn and D should be ready

Read/Write command Registration

READ if WEn = 4'hf

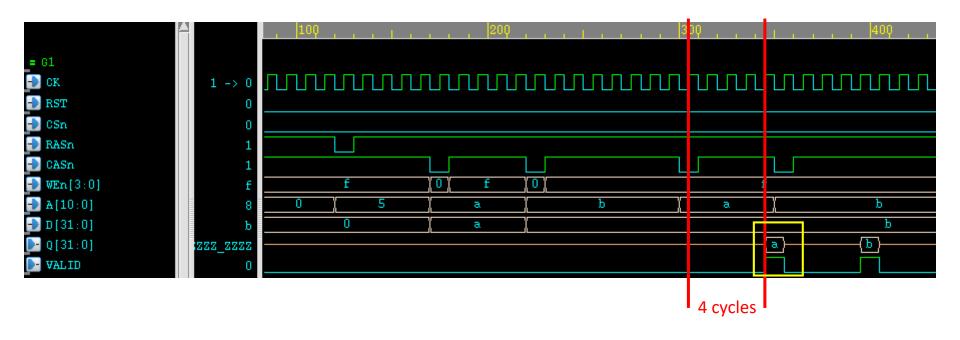
WRITE if WEn != 4'hf



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Waveform

- Read operation
 - Data will output with a valid signal



VLSI System Design (Graduate Level) Fall 2021

Thanks for listening